


<b>Search Notes</b>  	<b>Application/Control No.</b>  10652327	<b>Applicant(s)/Patent Under Reexamination</b>  ELZUR ET AL.
	<b>Examiner</b>  Hoang, Hieu T	<b>Art Unit</b>  2152

SEARCHED			
Class	Subclass	Date	Examiner
709	229, 230, 250	6/12/2007	HH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	6/12/2007	HH
NPL (Google, IETF, IEEE)	6/12/2007	HH

INTERFERENCE SEARCH			
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